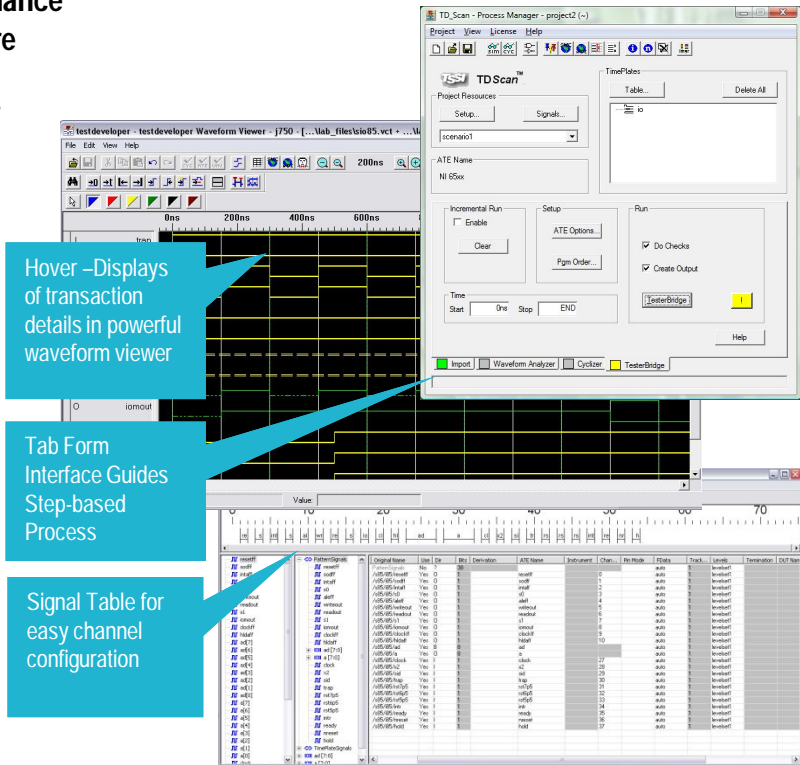


TD-Scan for National Instruments

DATASHEET

Flexible, Easy-to-Use, High Performance Test Program Development Software

- Reads WGL and STIL scan patterns
- Facilitates high-speed ATE programming for National Instrument's NI 65XX High Speed Digital I/O Series
- Flexible test-pattern generation options
- Powerful waveform viewer and intuitive graphical interface for interactive editing
- GUI or Batch Operation
- Seamless scalability up to TD-Sim, TestDeveloper, and the unix-based TDS package
- Works with National Instrument's LabVIEW graphical system design environment



TD-Scan's powerful graphical environment is easy to learn and use

TD-Scan is part of TSSI pattern conversion product suites: Test Development series (TDS), TestDeveloper (TD), TD-Sim, and TD-Scan. This scalable suite of products creates test programs from design data using powerful timing extraction and a managed process flow, reducing weeks of troubleshooting, enhancing engineering productivity and increasing first-time design success rates.

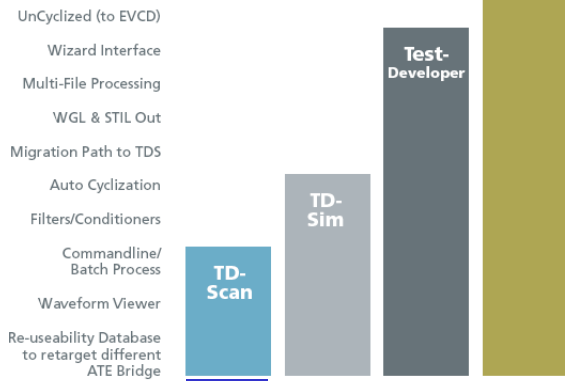
TD-Scan, as its name implies, supports primarily scan patterns from ATPG (automatic test pattern generation tools) outputs in the form of WGL (Waveform Generation Language) or STIL (Standard Test Interface Language).

For functional patterns in the form of VCD or EVCD, TD-Scan can be upgraded to TD-Sim or TestDeveloper by a simple license key; thereby, preserving all configuration and processed data.

For more demanding applications, upgrading to, or working in conjunction with the Unix-based TDS package is a popular choice.

TDS

- Self-documented flow
- Full Custom API
- 30+ EDA legacy Sim outputs
- 90+ ATE legacy models
- WGL/STIL Database
- Complete Conditioning Library
- Extensive Simulation Rules Check library
- Full ATE compressions: loops, subroutines, repeats



Seamless scalability up to other TD Tools for more functionalities



DATASHEET

TD-Scan for National Instruments and LabVIEW

TD-Scan for National Instruments is a result of the collaboration between TSSI and National Instruments (NI) to enable semiconductor test engineers to import WGL and IEEE 1450 Standard Test Interface Language (STIL) simulation vectors into NI PXI digital test systems.

TD-Scan for National Instruments produces LabVIEW data so that engineers can read and manipulate WGL and STIL vectors in LabVIEW graphical system design software and the NI Digital Waveform Editor, both of which provide control for all NI digital test hardware.

TD-Scan for National Instruments Key Capabilities:

- Waveform data generation and Instrument setup based on simulation output (WGL or STIL) file.
- Adjustable Sample Clock Rate to optimize waveform accuracy vs channel memory
- Automatic checks for maximum clock rate and edge delays across slots
- Automatic device channel assignment and customizable system board layout based on customer configuration
- Supported NI Instruments:
 - PXI/PCI-6541/6542
 - PXI/PCI-6544/6545
 - PXI/PCI-6547/6548
 - PXI/PCI-6551/6552
 - PXI/PCI-6561/6562

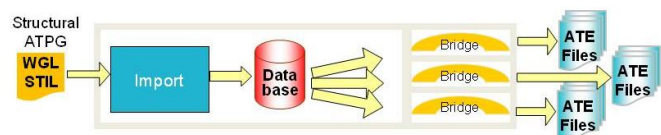
Saves Time with Intermediate Database

TD-Scan for National Instruments processes WGL and STIL files by first converting them into an intermediate database. Any subsequent data analysis and adjustment can be done directly to the database using the waveform viewer. Then, when ready, a TesterBridge for NI can be invoked to generate LabVIEW-ready data. For large patterns, this will save many conversion hours.

Modular Architecture Advantage

TD-Scan for National Instruments is also designed for users with multiple ATE platforms. Its modular architecture is ready for additional "Bridge" module, or TesterBridge, to be activated simply via license keys.

The intermediate database, again, saves time when targeting multiple platforms is required, validation to product retargeting, or simply for distributing ATE utilization.



Additional TesterBridges can be activated to support more ATEs

SUPPORTED ATEs

- ❖ Advantest: T33xx, T66xx, T65xx, SZ
- ❖ LTXCredence: Diamond, IMS, Kalos, Quartet/Octet, Schlumberger/NPTest ITS9000, Sapphire
- ❖ National Instruments: PXI/PCI-65XX
- ❖ Teradyne: J97x, Catalyst, Tiger, J750, Flex, UltraFlex, Nexttest
- ❖ Verigy: 83000, 9490, V93000 AIT and Binary

FLEXIBLE LICENSING

TD-Scan's flexible licensing model is designed to meet a variety of customer needs. Terms include monthly leasing, worldwide WAN, subscription, and perpetual licensing.

PLATFORM

- ❖ Windows NT/2000/XP/Vista
- ❖ Recommend Configuration: 8G RAM, 3GHz CPU Speed.

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